

# Dr. Kunal Singh

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## RESEARCH INTERESTS

Nanoelectronics, Non-Conventional Semiconductor device modeling using TCAD simulator, Fabrication and Characterization of Semiconductor Devices for Optoelectronics and Microelectronics applications.

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## PROFESSIONAL EXPERIENCE

- **National Institute of Technology, Jamshedpur, Jharkhand.**  
Duration: 06/2018 till date  
Working as Assistant Professor in Department of Electronics and Communication Engineering, NIT, Jamshedpur, Jharkhand.
- **Thapar University, Patiala, Punjab.**  
Duration: 07/2017 to 05/2018  
Worked as Lecturer in Department of Electronics and Communication, Thapar University, Patiala, Punjab.

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## EDUCATION

- **INDIAN INSTITUTE OF TECHNOLOGY (BHU), Varanasi**  
Doctor of Philosophy (Ph.D.) in Microelectronics  
Thesis Title: "Modeling and Simulation of Some Ultra Shallow Junction based Non-Conventional MOSFETs"

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## COURSES TAUGHT

- **At UG Level:**
  - VLSI Technology
  - Analog Electronics
  - Microelectronics and VLSI Design
- **At PG Level:**
  - Sensor Technology and MEMS.
  - Semiconductor device physics.

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## INVITED TALK

Delivered expert lecture in TEQIP-III sponsored ONE WEEK short course on "Modeling and Simulation of Advanced Semiconductor Devices & VLSI Circuits" scheduled on June 25-29, 2018 in the department of Electronics and Communication Engineering of this institute.

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## TECHNICAL PROGRAM COMMITTEE

**Joint Coordinator**, Department of Electronics and Communication Engineering, NIT Jamshedpur is conducting five days' workshop on "Hands on Introduction of HFSS in Microwave Applications" (WHFSSMA-2018) from 29th October to 2nd November.

## List of Articles Published

### Published Papers in International Journals

1. J. Talukdar, G. Rawat, B. Choudhuri, **K. Singh**, and K. Mummaneni, "Device Physics Based Analytical Modeling for Electrical Characteristics of Single Gate Extended Source Tunnel FET (SG-ESTFET)," *Superlattices Microstruct.*, p. 106725, 2020, doi: <https://doi.org/10.1016/j.spmi.2020.106725>. (Impact Factor: 2.123).
2. S. Kumar, **K. Singh**, K. Baral, P. K. Singh, and S. Jit, "2-D Analytical Model for Electrical Characteristics of Dual Metal Heterogeneous Gate Dielectric Double-Gate TFETs with Localized Interface Charges," *Silicon*, 2020, doi: 10.1007/s12633-020-00564-5.
3. R. Misra, **K. Singh**, M. Kumar, R. Rastogi, A. Kumar, and S. Dubey, "An Ultra-Low-Power Black Phosphorus (B-Ph)/Si Heterojunction Dopingless-Tunnel FET (HD-TFET) with Enhanced Electrical Characteristics," *Superlattices Microstruct.*, vol. 149, p. 106752, 2021, doi: <https://doi.org/10.1016/j.spmi.2020.106752>. (Impact Factor: 2.123).
4. J. Talukdar, G. Rawat, **K. Singh**, and K. Mummaneni, "Comparative Analysis of the Effects of Trap Charges on Single- and Double-Gate Extended-Source Tunnel FET with  $\delta p^+$  SiGe Pocket Layer," *J. Electron. Mater.*, vol. 49, no. 7, pp. 4333–4342, 2020, doi: 10.1007/s11664-020-08151-5. (Impact Factor: 1.579)
5. V. Purwar Gupta, Rajeev Kumar, Nitish Awasthi, Himanshi Dixit, Vijay Kumar, **Kunal Singh**, Sarvesh Dubey, Pramod Kumar Tiwari, "Investigating linearity and effect of temperature variation on analog/RF performance of dielectric pocket high-k double gate-all-around (DP-DGAA) MOSFETs," *Appl. Phys. A*, vol. 126, no. 9, p. 746, 2020, doi: 10.1007/s00339-020-03929-0. (Impact Factor: 1.75).
6. K. N. Priyadarshani, S. Singh, and **K. Singh**, "A Novel Self-Aligned Dopingless Symmetric Tunnel Field Effect Transistor (DL-STFET): A Process Variations Tolerant Design," *Silicon*, 2020, doi: 10.1007/s12633-020-00804-8. (Impact Factor: 1.5).
7. J. Talukdar, G. Rawat, **K. Singh**, and K. Mummaneni, "Low Frequency Noise Analysis of Single Gate Extended Source Tunnel FET," *Silicon*, 2020, doi: 10.1007/s12633-020-00712-x. (Impact Factor: 1.5).
8. **Kunal Singh**, S. Kumar, P.K Tiwari, A.B Yadav, S. Dubey and S. Jit, "Semianalytical Threshold Voltage Model of Double-Gate Nanoscale RingFET for Terahertz Applications in Radiation Hardened (Rad-Hard) Environments", *Journal of Electronic Materials*, Accepted, (2019), (Impact Factor: 1.579)
9. Basavaraj S Sannakashappanavar, C. R. Byrareddy, Nandini A. Pattanashetti, **Kunal Singh** and Aniruddh Bahadur Yadav, "Growth of ZnO Nanorods on Different Seed Layer Thickness Using the Hydrothermal Method for UV Detection", *Journal of Nanoelectronics and Optoelectronics*, Vol. 14, no. 7, July 2019, pp.964-971(8) (Impact Factor: 1.069).
10. **Kunal Singh**, Mirgender Kumar, Ekta Goel, Balraj Singh, Sarvesh Dubey, Sanjay Kumar, and Satyabrata Jit, "Analytical Modeling of Potential Distribution and Threshold Voltage of Gate Underlap DG MOSFETs with a Source/Drain Lateral Gaussian Doping Profile", *Journal of Electronic Materials*, Vol 45, pp. 2184-2192, (2016)(Impact Factor: 1.579)
11. **Kunal Singh**, Sanjay Kumar, Ekta Goel, Balraj Singh, Mirgender Kumar, Sarvesh Dubey and Satyabrata Jit, "Subthreshold Current and Swing Modeling of Gate Underlap DG MOSFETs with Source/Drain Lateral Gaussian Doping Profile", *Journal of Electronic Materials* vol. 46, no. 1, pp. 579–584, 2017.(Impact Factor: 1.579)
12. **Kunal Singh**, Sanjay Kumar, Ekta Goel, Balraj Singh, Sarvesh Dubey, and Satyabrata Jit, "Effects of Elevated Source/Drain and Side Spacer Dielectric on the Drivability Optimization of Non-abrupt Ultra Shallow Junction Gate Underlap DG MOSFETs" *Journal of Electronic Materials*, vol. 46, no. 1, pp. 520–526, 2017.(Impact Factor: 1.579)
13. **Kunal Singh**, S. Kumar, E. Goel, B. Singh, and S. Jit, "Effects of Source / Drain Elevation and Side Spacer Dielectric on Drivability Performance of Non- Abrupt Ultra Shallow Junction Gate Underlap GAA MOSFETs," *Indian Journal of physics*, Vol. 91, Issue1, pp. 171–176, 2018. (Impact Factor: 0.988)

14. Ekta Goel, Sanjay Kumar, **Kunal Singh**, Balraj Singh, Mirgender Kumar, and Satyabrata Jit, "2-D Analytical Modeling of Threshold Voltage for Graded-Channel Dual-Material Double-Gate MOSFETs", *IEEE Transactions on Electron Devices*, Vol 63, pp. 966-973, (2016). (Impact Factor: 2.605)
15. Ekta Goel, Balraj Singh, Sanjay Kumar, **Kunal Singh**, and Satyabrata Jit, "Analytical threshold voltage modeling of ion-implanted strained-Si double material double-gate (DMDG) MOSFETs", *Indian Journal of Physics*, Vol 91, Issue 4, pp 383–390 (2017) (Impact Factor: 0.988)
16. Ekta Goel, **Kunal Singh**, Balraj Singh, Sanjay Kumar, and Satyabrata Jit, "2-D Analytical Modeling of Subthreshold Current and Subthreshold Swing for Ion-implanted Strained-Si Double-Material Double-Gate (DMDG) MOSFETs", *Indian Journal of Physics*, Volume 91, [Issue 9](#), pp 1069–1076 (Impact Factor: 0.988)
17. Ekta Goel, Sanjay Kumar, Balraj Singh, **Kunal Singh** and Satyabrata Jit, "Two-dimensional model for subthreshold current and subthreshold swing of graded-channel dual-material double gate (GCDMDG) MOSFETs", *Superlattices and Microstructures*, Vol 106, 2017, pp 147-155, (Impact Factor: 2.123).
18. B. Singh, D. Gola, **K. Singh**, E. Goel, S. Kumar, and S. Jit, "2-D Analytical Threshold Voltage Model for Dielectric Pocket Double-Gate Junctionless FETs by Considering Source /Drain Depletion Effects," *IEEE Transactions Electron Devices*, vol. 64, no. 3, pp. 901–908, 2017. (Impact Factor: 2.605)
19. Balraj Singh, Deepti Gola, **Kunal Singh**, Ekta Goel, Sanjay Kumar and Satyabrata Jit, "Analytical Modeling of Subthreshold Characteristics of Ion-Implanted Symmetric Double Gate Junctionless Field Effect Transistors", *Materials Science in semiconductor processing*, Vol 58, pp. 82-88, (2017). (Impact Factor: 2.359)
20. Balraj Singh, Deepti Gola, **Kunal Singh**, Ekta Goel, Sanjay Kumar and Satyabrata Jit, "Analytical Modeling of Channel Potential and Threshold Voltage of Double Gate Junctionless Field Effect Transistors with a Vertical Gaussian-Like Doping Profile", *IEEE Transactions on Electron Devices*, Vol 63, pp. 2299-2305, (2016). (Impact Factor: 2.605)
21. Balraj Singh, Trailokya Nath Rai, Deepti Gola, **Kunal Singh**, Ekta Goel, Pramod Kumar Tiwari, Sanjay Kumar and Satyabrata Jit, "Ferro-Electric Stacked Gate Oxide Heterojunction Electro-Static Doped Source/Drain Double-Gate Tunnel Field Effect Transistors: A Superior Structure", *Materials Science in semiconductor processing*, Volume 71, 15 November 2017, Pages 161-165 (Impact Factor: 2.359).
22. Sanjay Kumar, Ekta Goel, **Kunal Singh**, Balraj Singh, Mirgender Kumar and Satyabrata Jit, "A Compact 2D Analytical Model for Electrical Characteristics of Double-Gate Tunnel Field-Effect Transistors with a SiO<sub>2</sub>/High-k Stacked Gate-Oxide Structure", *IEEE Transactions on Electron Devices* Vol 63, pp. 3291-3299, (2016). (Impact Factor: 2.605)
23. Sanjay Kumar, Ekta Goel, Kunal Singh, Balraj Singh, Prince Kumar Singh, Kamalaksha Baral and Satyabrata Jit "2-D Analytical Modeling of the Electrical Characteristics of Dual-Material Double- Gate TFETs With a SiO<sub>2</sub> / HfO<sub>2</sub> Stacked Gate-Oxide Structure," *IEEE Transactions on Electron Devices*, vol. 64, no. 3, pp. 960–968, 2017. (Impact Factor: 2.605).
24. Mirgender Kumar, Sanjay Kumar, Ekta Goel, **Kunal Singh**, Balraj Singh, and Satyabrata Jit, "Strain-Induced Plasma Radiation at Terahertz Domain in Strained-Si-on-Insulator MOSFETs", *IEEE Transactions on Plasma Science*, Vol. 44, no. 3, pp. 245-249. 2016 (Impact Factor: 0.958)
25. Balraj Singh, Deepti Gola, Ekta Goel, Sanjay Kumar, **Kunal Singh**, and Satyabrata Jit, "Dielectric Pocket Double Gate Junctionless FET: A New MOS Structure with Improved Subthreshold Characteristics for Low Power VLSI Applications", *Journal of Computational Electronics*, Vol 15, pp. 502-507, (2016) (Impact Factor: 1.526)
26. Pramod Kumar Tiwari, **Kunal Singh**, Sarvesh Dubey and S. Jit, "Analytical modeling for the subthreshold current and subthreshold swing of the triple-material double-gate (TM-

- DG) MOSFETs” ,**Superlattices and Microstructures**, 51 (2012) 715–724) (Impact Factor: 2.123)
27. H. Kumar, Y. Kumar, K. Singh, S. Kumar, G. Rawat, C. Kumar, B.N. Pal and S. Jit, “Kink Effect in TiO<sub>2</sub> Embedded ZnO Quantum Dot based Thin Film Transistors” **Electronics Letters**, 53(4):15–16, 2017. (Impact Factor: 1.0)
  28. AB Yadav, **Kunal Singh**, A Pandey and S Jit, "Annealing-temperature effects on the properties of ZnO thin films and Pd/ZnOSchottky contacts grown on n-Si (100) substrates by vacuum deposition method” ,**Superlattices and Microstructures**, 71 (2014) 250-260.(Impact Factor: 2.123)
  29. Sanjay Kumar , Kunal Singh, Sweta Chander, Ekta Goel, Prince Kumar Singh, Kamalaksha Baral, Balraj Singh and Satyabrata Jit, “2-D Analytical Drain Current Model of Double-Gate Heterojunction TFETs With a SiO<sub>2</sub>/HfO<sub>2</sub>/Stacked Gate-Oxide Structure”, **IEEE Transactions on Electron Devices** (Accepted) (2017). (Impact Factor: 2.605)
  30. Sweta Chander, Sanjeet Kumar Sinha, Sanjay Kumar, Prince Kumar Singh, KamalakshaBaral, **Kunal Singh** and Satyabrata Jit, "Temperature Analysis of Ge/Si Heterojunction SOI-Tunnel FET”,**Superlattices and Microstructures**,110 (2017) 162-170.(Impact Factor: 2.123).
  31. Shaivalini Singh, Pramod Kumar Tiwari, Hemant Kumar, Yogesh Kumar, Gopal Rawat, Sanjay Kumar, **Kunal Singh**, Ekta Goel, S. Jit, Si-Hyun Park" Theoretical and Experimental Study of UV Detection Characteristics of Pd/ZnONanorodSchottky Diodes”, **NANO**,Vol 12, 1750137-(1-8) (2017), (Impact Factor: 1.293).

#### **Articles in National/International Conferences**

1. **Kunal Singh**, Ekta Goel, Sanjay Kumar, Balraj Singh, M. Kumar and S. Jit, “Source/Drain Lateral Extension as Current On/Off ratio Booster in Gate Underlap DG MOSFETs with Source/Drain Lateral Gaussian Doping Profile”, *18<sup>th</sup> International Workshop on the Physics of Semiconductor Devices (IWPSD)*, @Indian Institute of Science, Bangalore, 2015.
2. EktaGoel, **Kunal Singh**, Sanjay Kumar, Balraj Singh, M. Kumar and S. Jit, “Impact of Heterogeneous Gate Dielectric on Strained Silicon Double-Gate Tunnel Field Effect Transistor”, *18<sup>th</sup> International Workshop on the Physics of Semiconductor Devices (IWPSD)*, @Indian Institute of Science, Bangalore, 2015.
3. Sanjay Kumar, EktaGoel, **Kunal Singh**, Balraj Singh, Mirgender Kumar, and S. Jit, “A 2D Analytical Model of Double-Gate (DG) Tunnel-Field-Effect Transistor (TFET): Impact of Shortest Tunneling Distance”, *18<sup>th</sup> International Workshop on the Physics of Semiconductor Devices (IWPSD)*, @Indian Institute of Science, Bangalore, 2015.
4. Sanjay Kumar, EktaGoel, GopalRawat, **Kunal Singh**, Mirgender Kumar, SarveshDubey and S. Jit, “Threshold Voltage Modeling of Short-Channel DG MOSFETs with Non-Uniform Doping in the Vertical Direction”, *17<sup>th</sup> International Workshop on the Physics of Semiconductor Devices (IWPSD)*, @Noida, India, 2013.
5. Sanjay Kumar, EktaGoel, **Kunal Singh**, Mirgender Kumar and S. Jit, “Surface Potential Based Subthreshold Current Modeling of DG MOSFETs with Non-uniform Doping in the Vertical Direction”, *4<sup>th</sup> International Conference on Current Developments in Atomic, Molecular & Optical Physics with Applications (CDAMOP-2015)*, 11<sup>th</sup>-14<sup>th</sup> March, 2015 held at University of Delhi, Delhi.
6. Mirgender Kumar, **Kunal Singh**, S. Kumar and S. Jit, Analytical Study of Hot-Carrier Induced Effect on Current Characteristics of Strained-Si (s-Si) on Silicon-Germanium-on-Insulator (SGOI) MOSFETs, *National Conference on Research & Innovations in Electronics and Communication Engineering*, @ Noida Institute of Engineering and Technology (NIET), on 10-11th Oct, 2014.

7. Balraj Singh ,Deepti Gola,Sanjay Kumar,**Kunal Singh**,Ekta Goel and Satyabrata Jit, Analytical Study of Hot-Carrier Induced Effect on Current Characteristics of Strained-Si (s-Si) on Silicon-Germanium-on-Insulator (SGOI) MOSFETs, *IEEE International Conference On Recent Trends In Electronics Information Communication Technology*, 10-11th Oct, 2014.